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#### Understanding <u>Embedded - CPLDs (Complex</u> <u>Programmable Logic Devices)</u>

Embedded - CPLDs, or Complex Programmable Logic Devices, are highly versatile digital logic devices used in electronic systems. These programmable components are designed to perform complex logical operations and can be customized for specific applications. Unlike fixedfunction ICs, CPLDs offer the flexibility to reprogram their configuration, making them an ideal choice for various embedded systems. They consist of a set of logic gates and programmable interconnects, allowing designers to implement complex logic circuits without needing custom hardware.

**Applications of Embedded - CPLDs** 

#### Details

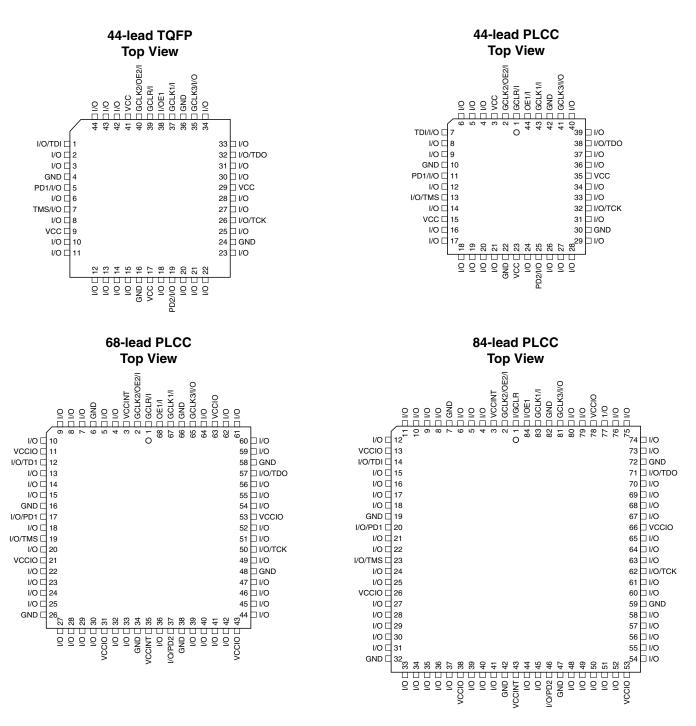
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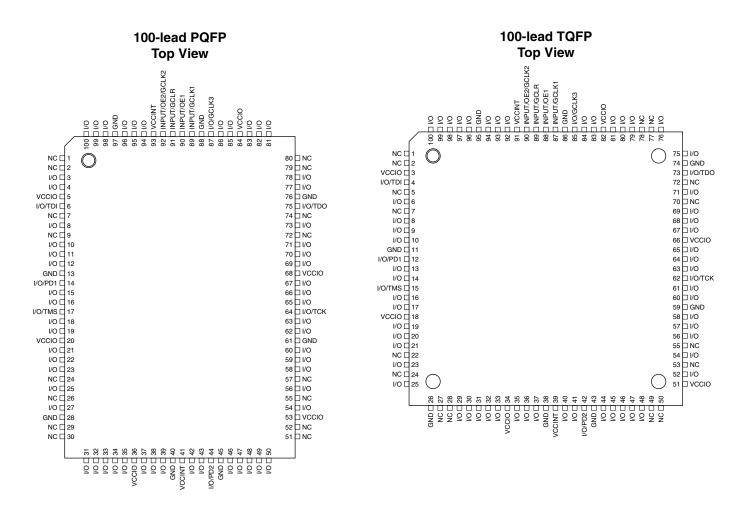
2 0 0 0 0 0	
Product Status	Obsolete
Programmable Type	In System Programmable (min 10K program/erase cycles)
Delay Time tpd(1) Max	15 ns
Voltage Supply - Internal	3V ~ 3.6V
Number of Logic Elements/Blocks	-
Number of Macrocells	64
Number of Gates	-
Number of I/O	32
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	44-TQFP
Supplier Device Package	44-TQFP (10x10)
Purchase URL	https://www.e-xfl.com/product-detail/microchip-technology/atf1504asv-15ai44

Email: info@E-XFL.COM

Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong











### Description

The ATF1504ASV(L) is a high-performance, high-density complex programmable logic device (CPLD) that utilizes Atmel's proven electrically-erasable memory technology. With 64 logic macrocells and up to 68 inputs, it easily integrates logic from several TTL, SSI, MSI, LSI and classic PLDs. The ATF1504ASV(L)'s enhanced routing switch matrices increase usable gate count and the odds of successful pin-locked design modifications.

The ATF1504ASV(L) has up to 68 bi-directional I/O pins and four dedicated input pins, depending on the type of device package selected. Each dedicated pin can also serve as a global control signal, register clock, register reset or output enable. Each of these control signals can be selected for use individually within each macrocell.

Each of the 64 macrocells generates a buried feedback that goes to the global bus. Each input and I/O pin also feeds into the global bus. The switch matrix in each logic block then selects 40 individual signals from the global bus. Each macrocell also generates a foldback logic term that goes to a regional bus. Cascade logic between macrocells in the ATF1504ASV(L) allows fast, efficient generation of complex logic functions. The ATF1504ASV(L) contains four such logic chains, each capable of creating sum term logic with a fan-in of up to 40 product terms.

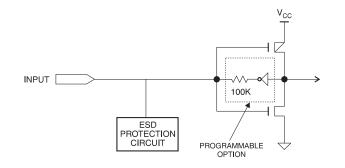
The ATF1504ASV(L) macrocell, shown in Figure 1, is flexible enough to support highlycomplex logic functions operating at high speed. The macrocell consists of five sections: product terms and product term select multiplexer, OR/XOR/CASCADE logic, a flip-flop, output select and enable, and logic array inputs.

OR/XOR/CASCADE Logic	The ATF1504ASV(L)'s logic structure is designed to efficiently support all types of logic. Within a single macrocell, all the product terms can be routed to the OR gate, creating a 5-input AND/OR sum term. With the addition of the CASIN from neighboring macrocells, this can be expanded to as many as 40 product terms with little additional delay.
	The macrocell's XOR gate allows efficient implementation of compare and arithmetic functions. One input to the XOR comes from the OR sum term. The other XOR input can be a product term or a fixed high- or low-level. For combinatorial outputs, the fixed level input allows polarity selection. For registered functions, the fixed levels allow DeMorgan minimization of product terms. The XOR gate is also used to emulate T- and JK-type flip-flops.
Flip-flop	The ATF1504ASV(L)'s flip-flop has very flexible data and control functions. The data input can come from either the XOR gate, from a separate product term or directly from the I/O pin. Selecting the separate product term allows creation of a buried registered feedback within a combinatorial output macrocell. (This feature is automatically implemented by the fitter software). In addition to D, T, JK and SR operation, the flip-flop can also be configured as a flow-through latch. In this mode, data passes through when the clock is high and is latched when the clock is low.
	The clock itself can either be one of the Global CLK Signal (GCK[0 : 2]) or an individual product term. The flip-flop changes state on the clock's rising edge. When the GCK signal is used as the clock, one of the macrocell product terms can be selected as a clock enable. When the clock enable function is active and the enable signal (product term) is low, all clock edges are ignored. The flip-flop's asynchronous reset signal (AR) can be either the Global Clear (GCLEAR), a product term, or always off. AR can also be a logic OR of GCLEAR with a product term. The asynchronous preset (AP) can be a product term or always off.
Extra Feedback	The ATF1504ASV(L) macrocell output can be selected as registered or combinatorial. The extra buried feedback signal can be either combinatorial or a registered signal regardless of whether the output is combinatorial or registered. (This enhancement function is automatically implemented by the fitter software.) Feedback of a buried com- binatorial output allows the creation of a second latch within a macrocell.
I/O Control	The output enable multiplexer (MOE) controls the output enable signal. Each I/O can be individually configured as an input, output or for bi-directional operation. The output enable for each macrocell can be selected from the true or compliment of the two output enable pins, a subset of the I/O pins, or a subset of the I/O macrocells. This selection is automatically done by the fitter software when the I/O is configured as an input, all macrocell resources are still available, including the buried feedback, expander and cascade logic.
Global Bus/Switch Matrix	The global bus contains all input and I/O pin signals as well as the buried feedback sig- nal from all 64 macrocells. The switch matrix in each logic block receives as its inputs all signals from the global bus. Under software control, up to 40 of these signals can be selected as inputs to the logic block.
Foldback Bus	Each macrocell also generates a foldback product term. This signal goes to the regional bus and is available to four macrocells. The foldback is an inverse polarity of one of the macrocell's product terms. The four foldback terms in each region allow generation of high fan-in sum terms (up to nine product terms) with little additional delay.

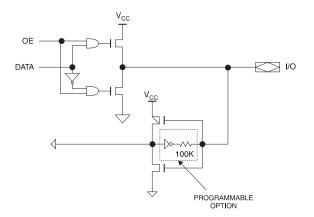
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## **Input Diagram**



### I/O Diagram



### Speed/Power Management

The ATF1504ASV(L) has several built-in speed and power management features. The ATF1504ASV(L) contains circuitry that automatically puts the device into a low power standby mode when no logic transitions are occurring. This not only reduces power consumption during inactive periods, but also provides proportional power savings for most applications running at system speeds below 5 MHz. This feature may be selected as a device option.

To further reduce power, each ATF1504ASV(L) macrocell has a reduced-power bit feature. This feature allows individual macrocells to be configured for maximum power savings. This feature may be selected as a design option.

All ATF1504ASV(L) also have an optional power-down mode. In this mode, current drops to below 5 mA. When the power-down option is selected, either PD1 or PD2 pins (or both) can be used to power down the part. The power-down option is selected in the design source file. When enabled, the device goes into power down when either PD1 or PD2 is high. In the power-down mode, all internal logic signals are latched and held, as are any enabled outputs.

All pin transitions are ignored until the PD pin is brought low. When the power-down feature is enabled, the PD1 or PD2 pin cannot be used as a logic input or output. However, the pin's macrocell may still be used to generate buried foldback and cascade logic signals.

	All power-down AC characteristic parameters are computed from external input or I/O pins, with reduced-power bit turned on. For macrocells in reduced-power mode (reduced-power bit turned on), the reduced-power adder, $t_{RPA}$ , must be added to the AC parameters, which include the data paths $t_{LAD}$ , $t_{LAC}$ , $t_{IC}$ , $t_{ACH}$ and $t_{SEXP}$ .
	The ATF1504ASV(L) macrocell also has an option whereby the power can be reduced on a per macrocell basis. By enabling this power-down option, macrocells that are not used in an application can be turned down, thereby reducing the overall power con- sumption of the device.
	Each output also has individual slew rate control. This may be used to reduce system noise by slowing down outputs that do not need to operate at maximum speed. Outputs default to slow switching, and may be specified as fast switching in the design file.
Design Software Support	ATF1504ASV(L) designs are supported by several industry standard third party tools. Automated fitters allow logic synthesis using a variety of high-level description lan- guages and formats.
Power-up Reset	<ul> <li>The ATF1504ASV is designed with a power-up reset, a feature critical for state machine initialization. At a point delayed slightly from V<sub>CC</sub> crossing V<sub>RST</sub>, all registers will be initialized, and the state of each output will depend on the polarity of its buffer. However, due to the asynchronous nature of reset and uncertainty of how V<sub>CC</sub> actually rises in the system, the following conditions are required:</li> <li>1. The V<sub>CC</sub> rise must be monotonic,</li> <li>2. After reset occurs, all input and feedback setup times must be met before driving the clock pin high, and,</li> </ul>
	3. The clock must remain stable during $T_{\rm D}$ .
	The ATF1504ASV has two options for the hysteresis about the reset level, V <sub>RST</sub> , Small and Large. To ensure a robust operating environment in applications where the device is operated near 3.0V, Atmel recommends that during the fitting process users configure the device with the Power-up Reset hysteresis set to Large. For conversions, Atmel POF2JED users should include the flag "-power_reset" on the command line after "file-name.POF". To allow the registers to be properly reinitialized with the Large hysteresis option selected, the following condition is added:
	<ol> <li>If V<sub>CC</sub> falls below 2.0V, it must shut off completely before the device is turned on again.</li> </ol>
	When the Large hysteresis option is active, I <sub>CC</sub> is reduced by several hundred micro- amps as well.
Security Fuse Usage	A single fuse is provided to prevent unauthorized copying of the ATF1504ASV(L) fuse patterns. Once programmed, fuse verify is inhibited. However, the 16-bit User Signature remains accessible.



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Programming	ATF1504ASV(L) devices are in-system programmable (ISP) devices utilizing the 4-pin JTAG protocol. This capability eliminates package handling normally required for pro- gramming and facilitates rapid design iterations and field changes.
	Atmel provides ISP hardware and software to allow programming of the ATF1504ASV(L) via the PC. ISP is performed by using either a download cable, a comparable board tester or a simple microprocessor interface.
	To facilitate ISP programming by the Automated Test Equipment (ATE) vendors. Serial Vector Format (SVF) files can be created by Atmel provided software utilities.
	ATF1504ASV(L) devices can also be programmed using standard third-party program- mers. With third-party programmer the JTAG ISP port can be disabled thereby allowing four additional I/O pins to be used for logic.
	Contact your local Atmel representatives or Atmel PLD applications for details.
ISP Programming Protection	The ATF1504ASV(L) has a special feature that locks the device and prevents the inputs and I/O from driving if the programming process is interrupted for any reason. The inputs and I/O default to high-Z state during such a condition. In addition the pin keeper option preserves the former state during device programming, if this circuit were previ- ously programmed on the device. This prevents disturbing the operation of other circuits in the system while the ATF1504ASV(L) is being programmed via ISP.
	All ATF1504ASV(L) devices are initially shipped in the erased state thereby making them ready to use for ISP.
	Note: For more information refer to the "Designing for In-System Programmability with Atmel CPLDs" application note.

## **DC and AC Operating Conditions**

	Commercial	Industrial
Operating Temperature (Ambient))	0°C - 70°C	-40°C - 85°C
V <sub>CC</sub> (3.3V) Power Supply	3.0V - 3.6V	3.0V - 3.6V

## **DC Characteristics**

Symbol	Parameter	Condition			Min	Тур	Max	Units
I <sub>IL</sub>	Input or I/O Low Leakage Current	$V_{IN} = V_{CC}$				-2	-10	μA
I <sub>IH</sub>	Input or I/O High Leakage Current					2	10	
I <sub>OZ</sub>	Tri-State Output Off-State Current	$V_{O} = V_{CC}$ or G	ND		-40		40	μA
			Obd Maida	Com.		60		mA
1	Power Supply Current,	V <sub>CC</sub> = Max	Std Mode	Ind.		75		mA
I <sub>CC1</sub>	Standby	$V_{IN} = 0, V_{CC}$	<b>((1.2) N A - - 1 -</b>	Com.		5		μA
			"L" Mode	Ind.		5		μA
I <sub>CC2</sub>	Power Supply Current, Power-down Mode	$V_{CC} = Max$ $V_{IN} = 0, V_{CC}$	"PD" Mode			0.1	5	mA
. (2)	Reduced-power Mode	V <sub>CC</sub> = Max	0115	Com		40		ma
I <sub>CC3</sub> <sup>(2)</sup>	Supply Current, Standby	$V_{IN} = 0, V_{CC}$		Ind		55		
V <sub>IL</sub>	Input Low Voltage				-0.3		0.8	V
V <sub>IH</sub>	Input High Voltage				1.7		V <sub>CCIO</sub> + 0.3	V
		$V_{IN} = V_{IH} \text{ or } V_{I}$	1	Com.			0.45	V
	Output Low Voltage (TTL)	$V_{CCIO} = Min, I_{OL} = 8 mA$	<sub>DL</sub> = 8 mA	Ind.			0.45	
V <sub>OL</sub>		$V_{IN} = V_{IH} \text{ or } V_{I}$	I	Com.			0.2	V
		$V_{CC} = Min, I_{OL}$		Ind.			0.2	V
.,	Output High Voltage - 3.3V (TTL)	$V_{IN} = V_{IH} \text{ or } V_{I}$ $V_{CCIO} = Min, I_{O}$		- F	2.4			V
V <sub>OH</sub>	Output High Voltage - 3.3V (CMOS)		$V_{IN} = V_{IH} \text{ or } V_{IL}$ $V_{CCIO} = \text{Min}, I_{OH} = -0.1 \text{ mA}$		V <sub>CCIO</sub> - 0.2			V

Notes: 1. Not more than one output at a time should be shorted. Duration of short circuit test should not exceed 30 sec. 2. When microcell reduced-power feature is enabled.

## **Pin Capacitance**

	Тур	Max	Units	Conditions
C <sub>IN</sub>		8	pF	V <sub>IN</sub> = 0V; f = 1.0 MHz
C <sub>I/O</sub>		8	pF	$V_{OUT} = 0V$ ; f = 1.0 MHz

Note: Typical values for nominal supply voltage. This parameter is only sampled and is not 100% tested. The OGI pin (high-voltage pin during programming) has a maximum capacitance of 12 pF.



## **AC Characteristics**

		-1	15	-20		
Symbol	Parameter	Min	Max	Min	Max	Units
t <sub>PD1</sub>	Input or Feedback to Non-Registered Output	3	15		20	ns
t <sub>PD2</sub>	I/O Input or Feedback to Non-Registered Feedback	3	12		16	ns
t <sub>SU</sub>	Global Clock Setup Time	11		13.5		ns
t <sub>H</sub>	Global Clock Hold Time	0		0		ns
t <sub>FSU</sub>	Global Clock Setup Time of Fast Input	3		3		ns
t <sub>FH</sub>	Global Clock Hold Time of Fast Input	1.0		2		MHz
t <sub>COP</sub>	Global Clock to Output Delay		9		12	ns
t <sub>CH</sub>	Global Clock High Time	5		6		ns
t <sub>CL</sub>	Global Clock Low Time	5		6		ns
t <sub>ASU</sub>	Array Clock Setup Time	5		7		ns
t <sub>AH</sub>	Array Clock Hold Time	4		4		ns
t <sub>ACOP</sub>	Array Clock Output Delay		15		18.5	ns
t <sub>ACH</sub>	Array Clock High Time	6		8		ns
t <sub>ACL</sub>	Array Clock Low Time	6		8		ns
t <sub>CNT</sub>	Minimum Clock Global Period		13		17	ns
f <sub>CNT</sub>	Maximum Internal Global Clock Frequency	76.9		66		MHz
t <sub>ACNT</sub>	Minimum Array Clock Period		13		17	ns
f <sub>ACNT</sub>	Maximum Internal Array Clock Frequency	76.9		58.8		MHz
f <sub>MAX</sub>	Maximum Clock Frequency	100		83.3		MHz
t <sub>IN</sub>	Input Pad and Buffer Delay		2		2.5	ns
t <sub>IO</sub>	I/O Input Pad and Buffer Delay		2		2.5	ns
t <sub>FIN</sub>	Fast Input Delay		2		2	ns
t <sub>SEXP</sub>	Foldback Term Delay		8		10	ns
t <sub>PEXP</sub>	Cascade Logic Delay		1		1	ns
t <sub>LAD</sub>	Logic Array Delay		6		8	ns
t <sub>LAC</sub>	Logic Control Delay		3.5		4.5	ns
t <sub>IOE</sub>	Internal Output Enable Delay		3		3	ns
t <sub>OD1</sub>	Output Buffer and Pad Delay (Slow slew rate = OFF; $V_{CCIO} = 5V$ ; $C_L = 35 \text{ pF}$ )		3		4	ns
t <sub>OD2</sub>	Output Buffer and Pad Delay (Slow slew rate = OFF; $V_{CCIO} = 3.3V$ ; $C_L = 35 \text{ pF}$ )		3		4	ns
t <sub>OD3</sub>	Output Buffer and Pad Delay (Slow slew rate = ON; $V_{CCIO}$ = 5V or 3.3V; $C_L$ = 35 pF)		5		6	ns
t <sub>ZX1</sub>	Output Buffer Enable Delay (Slow slew rate = OFF; $V_{CCIO} = 5.0V$ ; $C_L = 35 \text{ pF}$ )		7		9	ns



### **Power-down Mode**

The ATF1504ASV(L) includes an optional pin-controlled power-down feature. When this mode is enabled, the PD pin acts as the power-down pin. When the PD pin is high, the device supply current is reduced to less than 3 mA. During power down, all output data and internal logic states are latched internally and held. Therefore, all registered and combinatorial output data remain valid. Any outputs that were in a High-Z state at the onset will remain at High-Z. During power down, all input signals except the power-down pin are blocked. Input and I/O hold latches remain active to ensure that pins do not float to indeterminate levels, further reducing system power. The power-down mode feature is enabled in the logic design file or as a fitted or translated s/w option. Designs using the power-down pin may not use the PD pin as a logic array input. However, all other PD pin macrocell resources may still be used, including the buried feedback and foldback product term array inputs.

		-	15	-20		
Symbol	Parameter	Min	Max	Min	Max	Units
t <sub>IVDH</sub>	Valid I, I/O before PD High	15		20		ns
t <sub>GVDH</sub>	Valid OE <sup>(2)</sup> before PD High	15		20		ns
t <sub>CVDH</sub>	Valid Clock <sup>(2)</sup> before PD High	15		20		ns
t <sub>DHIX</sub>	I, I/O Don't Care after PD High		25		30	ns
t <sub>DHGX</sub>	OE <sup>(2)</sup> Don't Care after PD High		25		30	ns
t <sub>DHCX</sub>	Clock <sup>(2)</sup> Don't Care after PD High		25		30	ns
t <sub>DLIV</sub>	PD Low to Valid I, I/O		1		1	μs
t <sub>DLGV</sub>	PD Low to Valid OE (Pin or Term)		1		1	μs
t <sub>DLCV</sub>	PD Low to Valid Clock (Pin or Term)		1		1	μs
t <sub>DLOV</sub>	PD Low to Valid Output		1		1	μs

## Power Down AC Characteristics<sup>(1)(2)</sup>

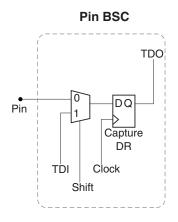
Notes: 1. For slow slew outputs, add t<sub>SSO</sub>.

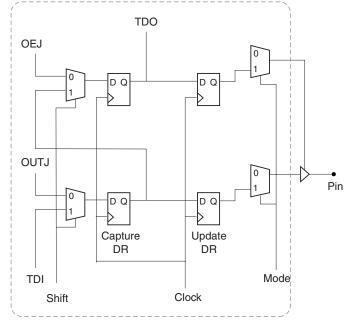
2. Pin or product term.

3. Includes  $t_{RPA}$  for reduced-power bit enabled.



# **BSC Configuration for Macrocell**





Macrocell BSC





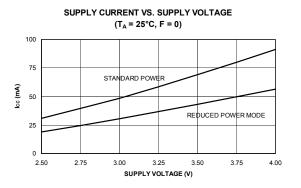
## **ATF1504ASV Dedicated Pinouts**

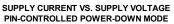
44-lead TQFP	44-lead J-lead	68-lead J-lead	84-lead J-lead	100-lead PQFP	100-lead TQFP
40	2	2	2	92	90
39	1	1	1	91	89
38	44	68	84	90	88
37	43	67	83	89	87
35	41	65	81	87	85
5, 19	11, 25	17, 37	20, 46	14, 44	12, 42
1	7	12	14	6	4
7	13	19	23	17	15
26	32	50	62	64	62
32	38	57	71	75	73
4, 16, 24, 36	10, 22, 30, 42	6, 16, 26, 34, 38, 48, 58, 66	7, 19, 32, 42, 47, 59, 72, 82	13, 28, 40, 45, 61, 76, 88, 97	11, 26, 38, 43, 59, 74, 86, 95
9, 17, 29, 41	3, 15, 23, 35	3, 11, 21, 31, 35, 43, 53, 63	3,13, 26, 38, 43, 53, 66, 78	5, 20, 36, 41, 53, 68, 84, 93	3, 18, 34, 39, 51, 66, 82, 91
_	_	_	_	1, 2, 7, 9, 24, 26, 29, 30, 51, 52, 55, 57, 72, 74, 79, 80	1, 2, 5, 7, 22, 24, 27, 28, 49, 50, 53, 55, 70, 72, 77, 78
36	36	52	68	68	68
32	32	48	64	64	64
Global	OE pins		I		I
Global	Clear pin				
Global	Clock pins				
Power-o	down pins				
JTAG p	ins used for bour	dary-scan testing	g or in-system pro	ogramming	
Ground	pins				
	TQFP           40           39           38           37           35           5, 19           1           7           26           32           4, 16, 24, 36           9, 17, 29, 41           -           36           32           Global of Globa	TQFP       J-lead         40       2         39       1         38       44         37       43         35       41         5, 19       11, 25         1       7         7       13         26       32         32       38         4, 16, 24, 36       10, 22, 30, 42         9, 17, 29, 41       3, 15, 23, 35         -       -         36       36         32       32         36       36         32       32         32       32         36       36         32       32         32       32         32       32         32       32         Global ∪E pins       Global ∪ex pin         Global ∪ex pins       Power-wn pins	TQFP         J-lead         J-lead           40         2         2           39         1         1           38         44         68           37         43         67           35         41         65           5, 19         11, 25         17, 37           1         7         12           7         13         19           26         32         50           32         38         57           4, 16, 24, 36         10, 22, 30, 42         6, 16, 26, 34, 38, 48, 58, 66           9, 17, 29, 41         3, 15, 23, 35         3, 11, 21, 31, 35, 43, 53, 63           -         -         -         -           36         36         52           32         32         48           Global OE pins         Global Clear pin         Global Clear pin           Global Clock pins         Power-down pins         JTAG pins used for boundary-scan testing	TQFP         J-lead         J-lead         J-lead           40         2         2         2           39         1         1         1           38         44         68         84           37         43         67         83           35         41         65         81           5, 19         11, 25         17, 37         20, 46           1         7         12         14           7         13         19         23           26         32         50         62           32         38         57         71           4, 16, 24, 36         10, 22, 30, 42         6, 16, 26, 34, 3, 47, 59, 72, 82         3, 13, 26, 38, 35, 43, 53, 63           9, 17, 29, 41         3, 15, 23, 35         3, 11, 21, 31, 3, 13, 26, 38, 43, 53, 66, 78         36           36         36         52         68           32         32         48         64           Global Clear pin         Global Clear pin         Global Cleck pins         Global Cleck pins           Power-down pins         JTAG pins used for boundary-scan testing or in-system protect         48	TOFP         J-lead         J-lead         J-lead         PQFP           40         2         2         2         92           39         1         1         1         91           38         44         68         84         90           37         43         67         83         89           35         41         65         81         87           5, 19         11, 25         17, 37         20, 46         14, 44           1         7         12         14         6           7         13         19         23         17           26         32         50         62         64           32         38         57         71         75           4, 16, 24, 36         10, 22, 30, 42         6, 16, 26, 34, 3, 31, 29, 32, 42, 47, 59, 72, 82         61, 76, 88, 97           9, 17, 29, 41         3, 15, 23, 35         3, 11, 21, 31, 35, 43, 53, 63         43, 53, 66, 78         53, 68, 84, 93           -         -         -         -         -         -         1, 2, 7, 9, 24, 26, 29, 30, 51, 52, 55, 57, 72, 72, 74, 79, 80           36         36         52         68         68         68 </td

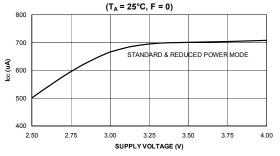
VCC

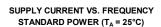
VCC pins for the device

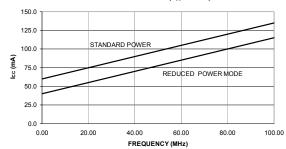


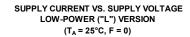


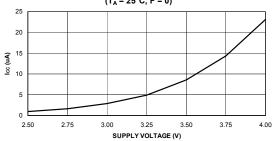


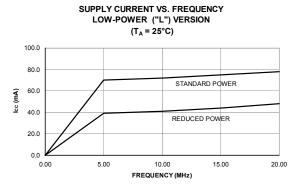


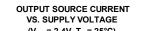


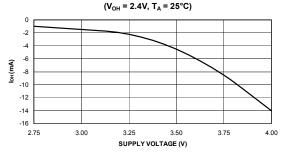


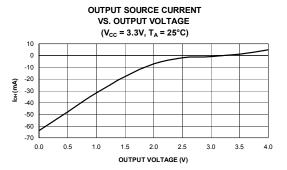


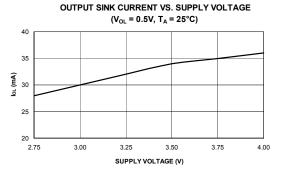










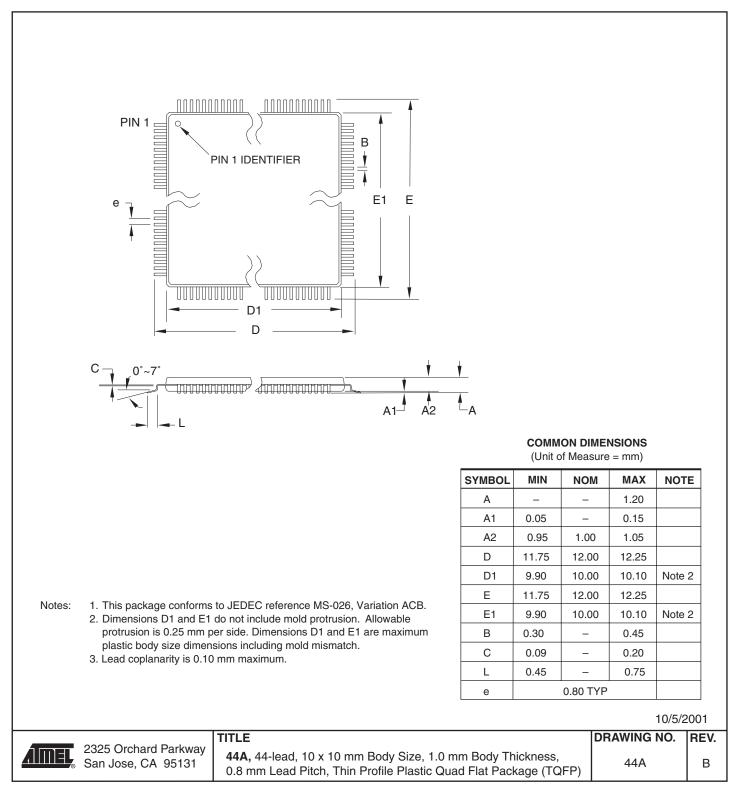


20

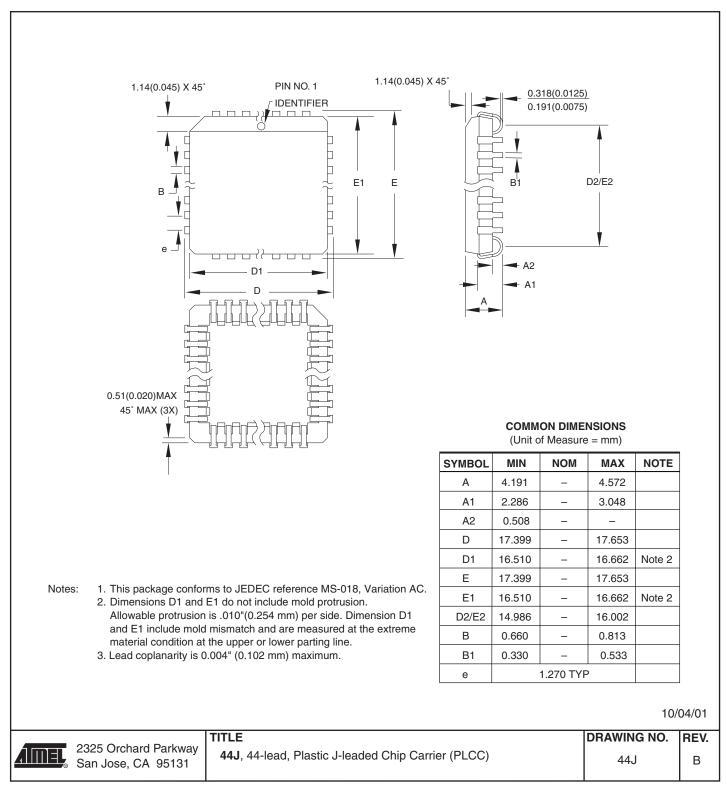


## **Packaging Information**

### 44A – TQFP



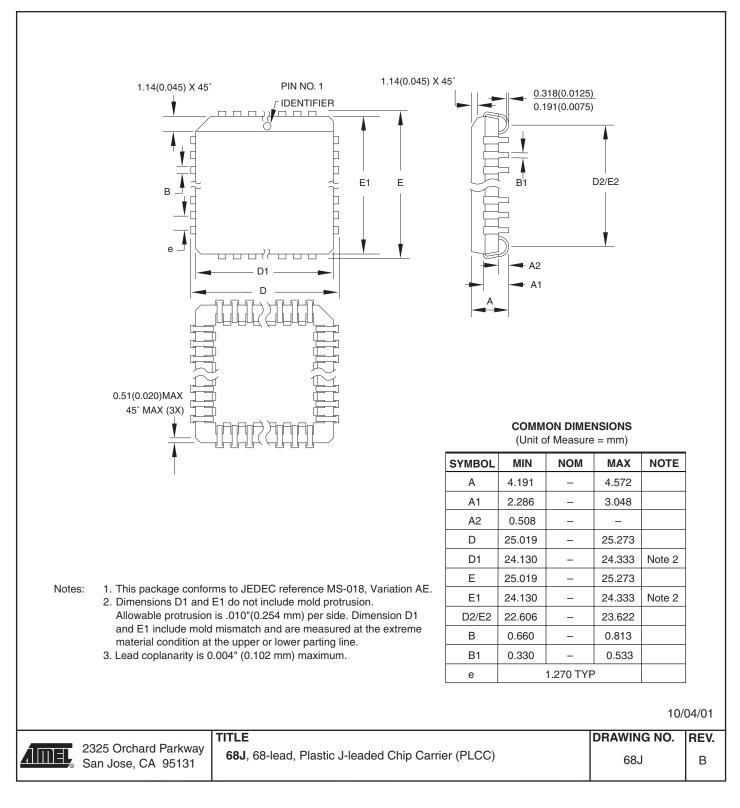
### 44J – PLCC



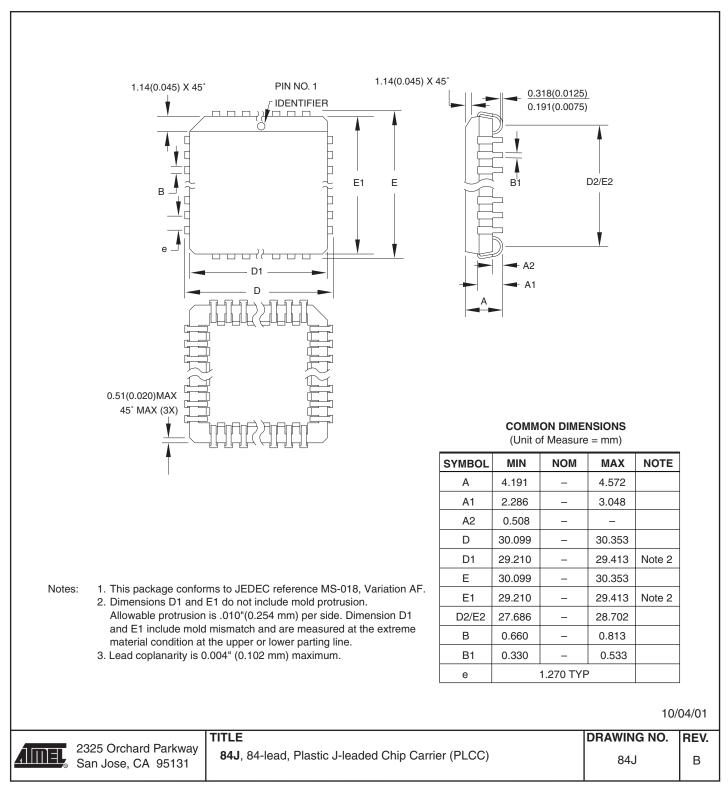




#### 68J – PLCC



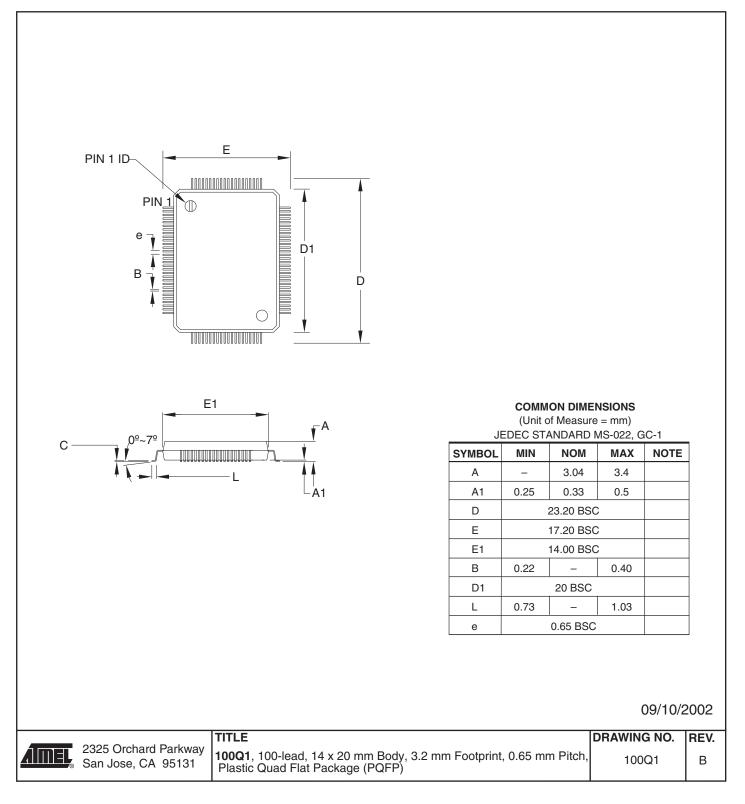
### 84J – PLCC







### 100Q1 - PQFP





# **Revision History**

Revision	Comments
1409J	Green package options added.



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